

Prognostics and Health Management of safety relevant electronics for future application in autonomous driving

Reinventing reliability in the era of disruption and creativity

Accuracy and
Uncertainty

Data-driven approach

Model-driven
approach for failure
prediction

Surrogate
Modelling

Aging/Drifting
Effects

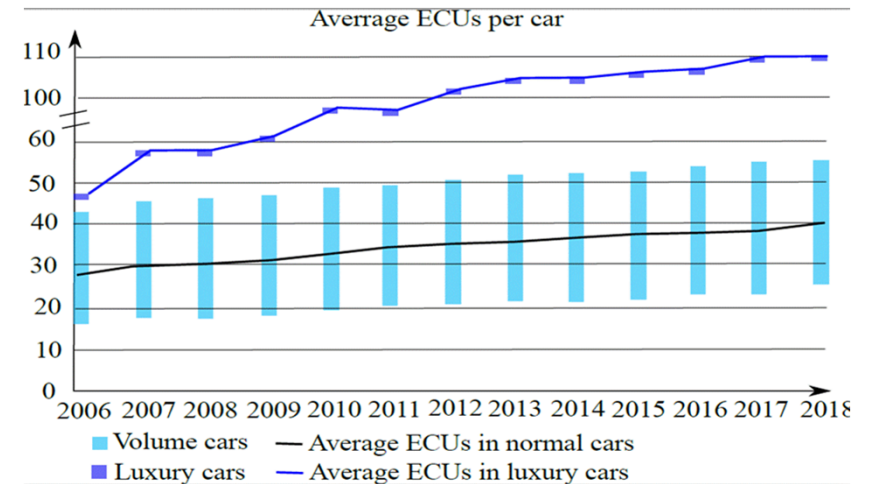


Introduction

Background and Motivation



Fig: Electronic control unit



The Electronic Control Unit (ECU) is used to control the engine and other components functions.

Introduction

Background and Motivation

Challenges

Autonomous driving

Costs

Short-time-to-market

System Availability

New Design

New Functions

Consumer Electronics

Motivation

Functional Safety

Redundancy reduction

Real load collectives

Mobility Service

Heterogeneous integration

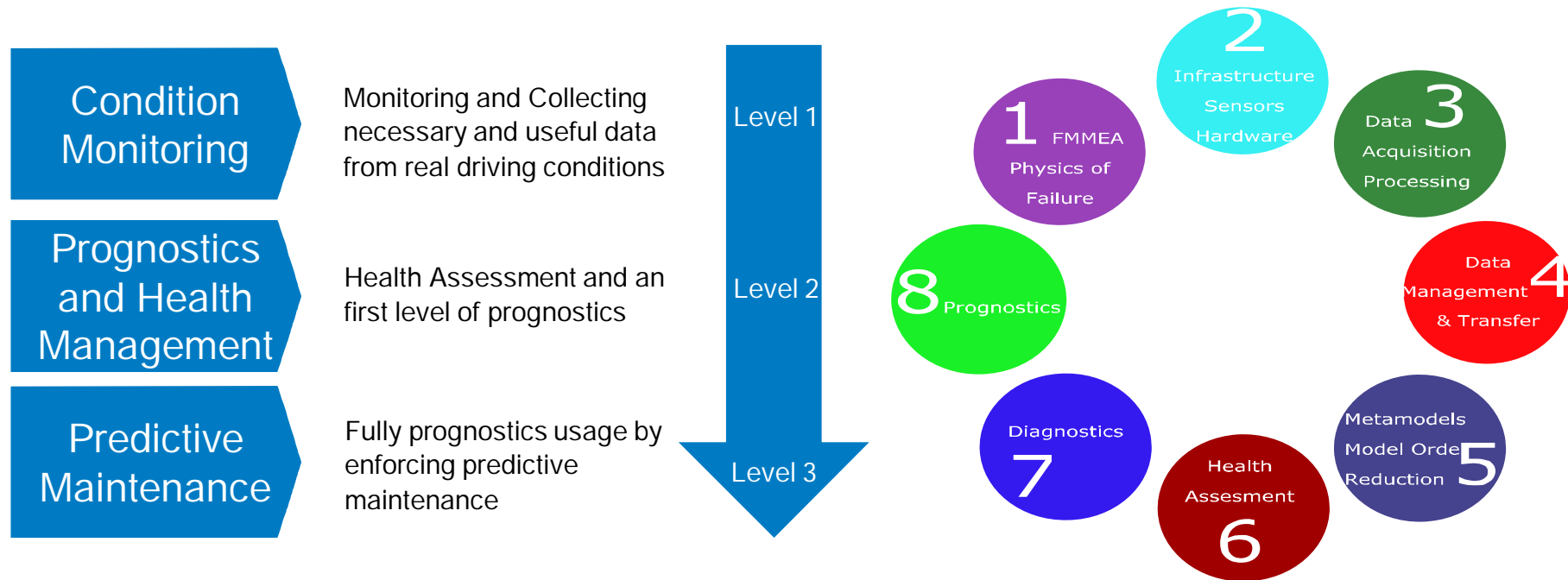
Internet of Things

Fast qualification

Prognostics and Health Management can be an answer to all these challenges

Introduction

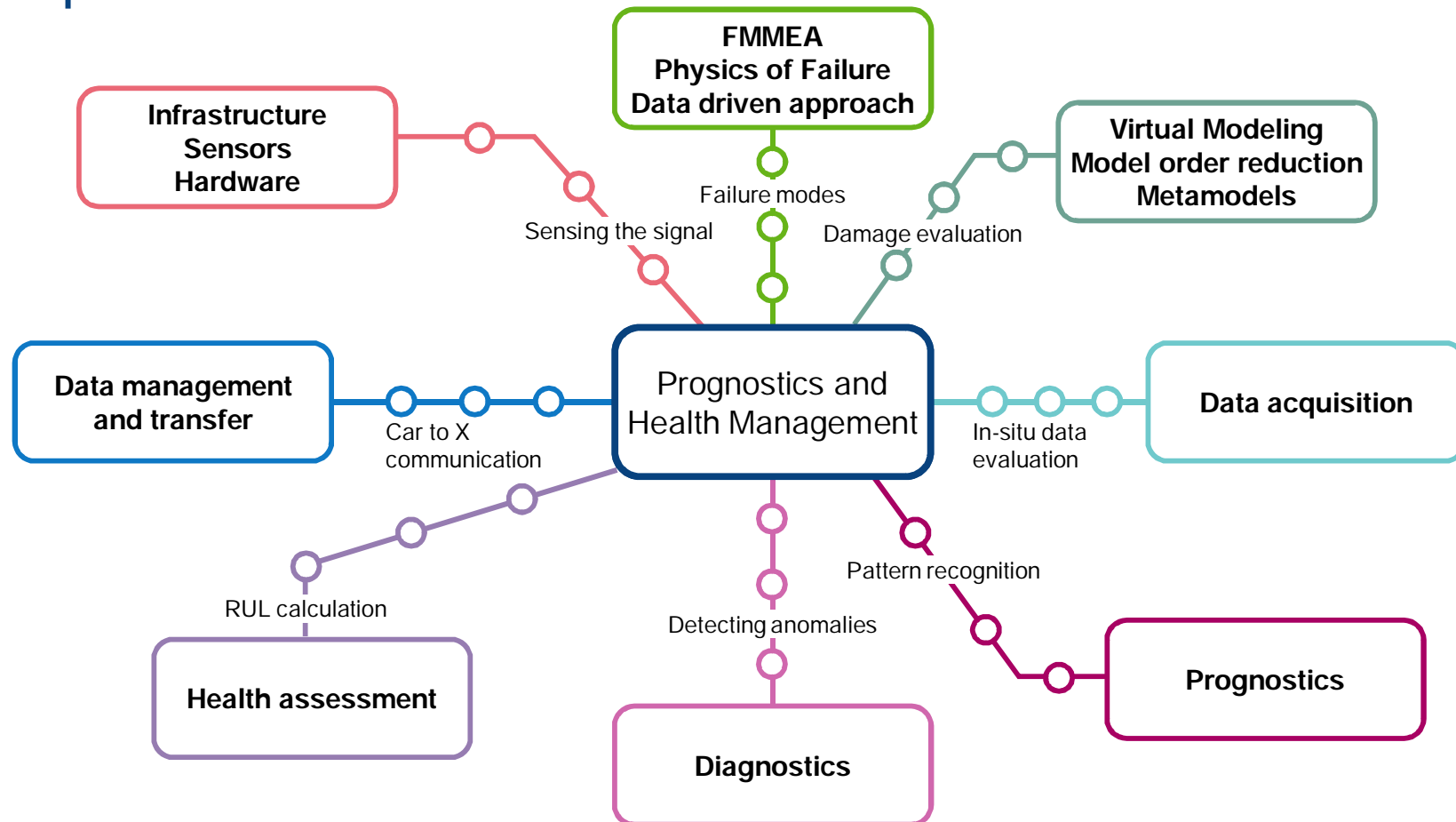
Background and Motivation



Prognostication level to be done in steps

Introduction

Metro map



Concept of PHM

iForce – piezoresistive stress sensor

Piezoresistive silicon based stress sensor: IForce – in-situ measurements of the stress state inside IC package

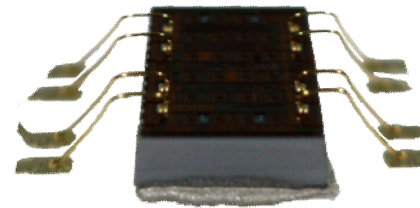
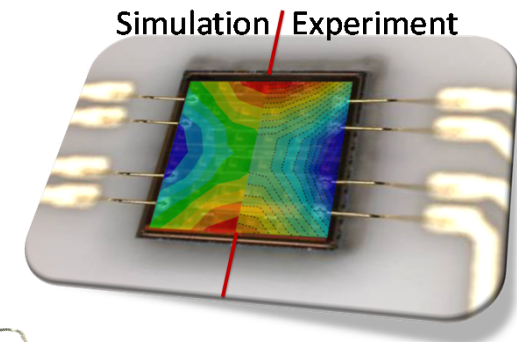
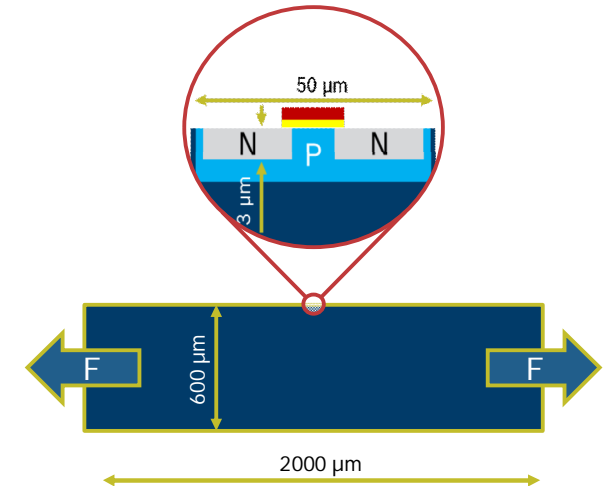
- ▶ Localized mechanical stress measurements during active operation and field condition
- ▶ Detection of the crack/delamination during active operation and field condition of the ASICs and power module
- ▶ Understanding the state of health: healthy / unhealthy
- ▶ Damage evolution using direct damage relevant quantity:
 - ▶ Mechanical stress difference;

$$\sigma_D = \sigma_x - \sigma_y = \frac{2}{\pi_{44}^{(p)}} \frac{\Delta I}{I}$$

- ▶ Shear stress.

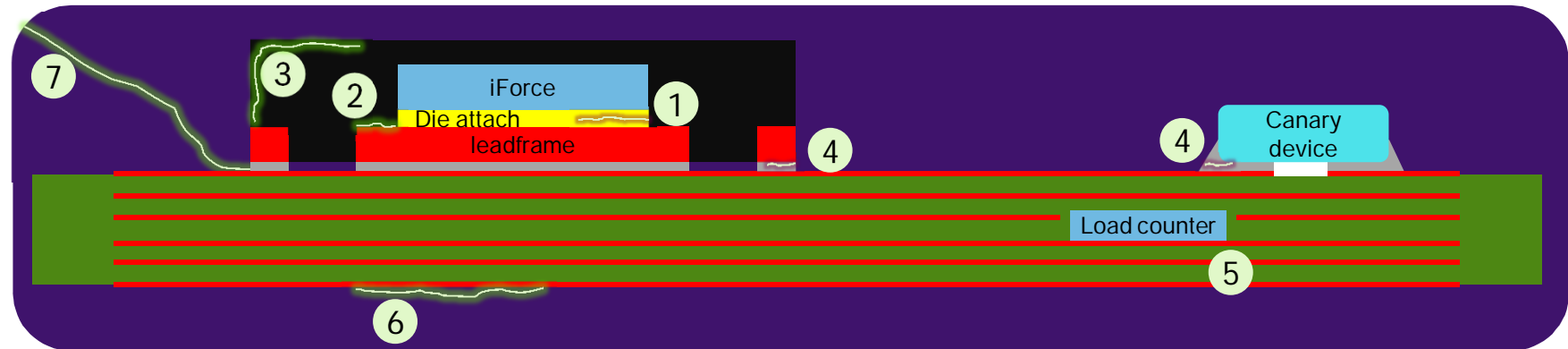
$$\sigma_{xy} = -\frac{1}{\pi_{11}^{(n)} - \pi_{12}^{(n)}} \frac{\Delta I}{I}$$

$$\frac{\Delta I}{I} \approx -\frac{\Delta R}{R}$$



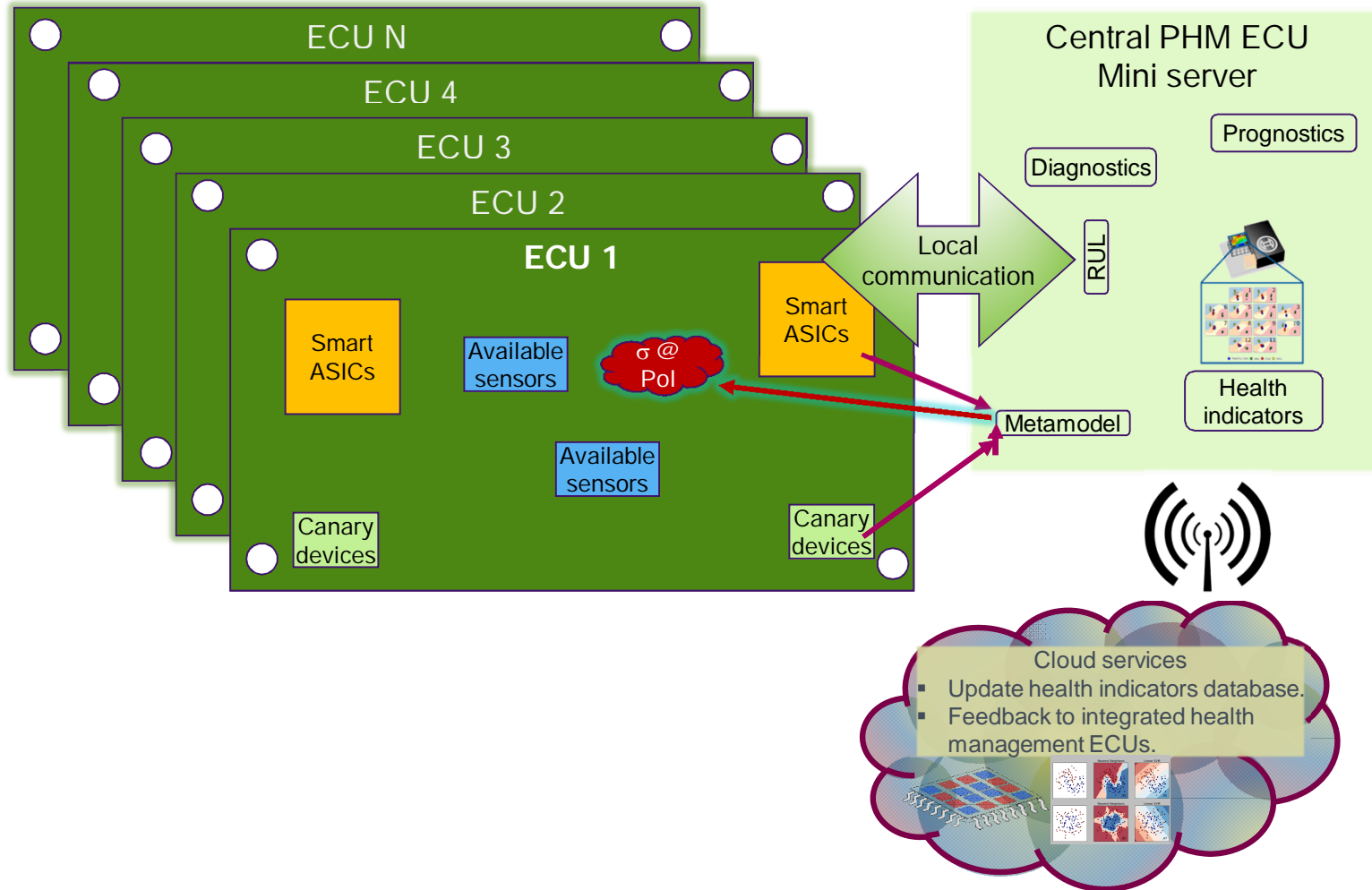
Failure modes

Investigated failure modes → packaging and ECU level



- 1 Delamination in the die attach → data driven approach with iForce
- 2 Delamination mold/copper lead frame → data driven approach with iForce
- 3 Aging of polymers → data driven approach with iForce
- 4 Solder fatigue → PoF and event detector (canary devices / -features)
- 5 Aging of other components → data driven approach with iForce
- 6 Delamination PCB / Mold
- 7 Crack mold

Integrated health management ECU Concept



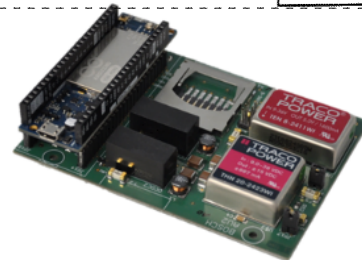
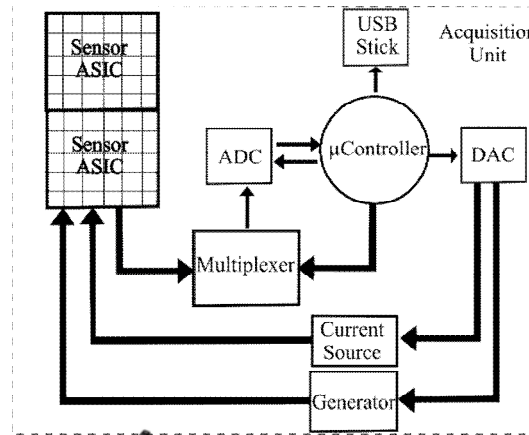
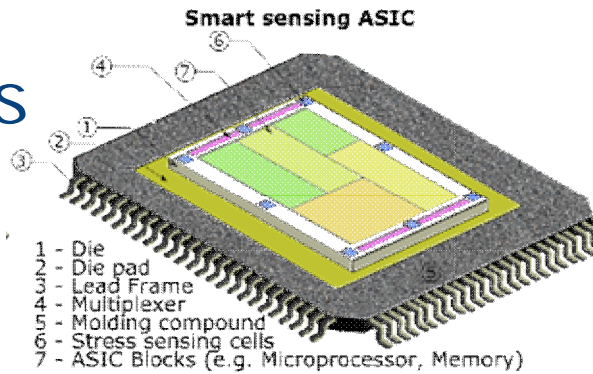
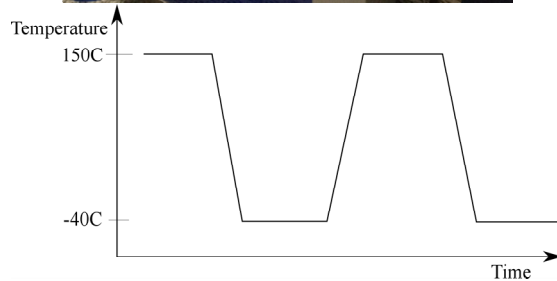
Data-driven Approach

Degradation Prediction of electronic packages using piezoresistive stress sensor

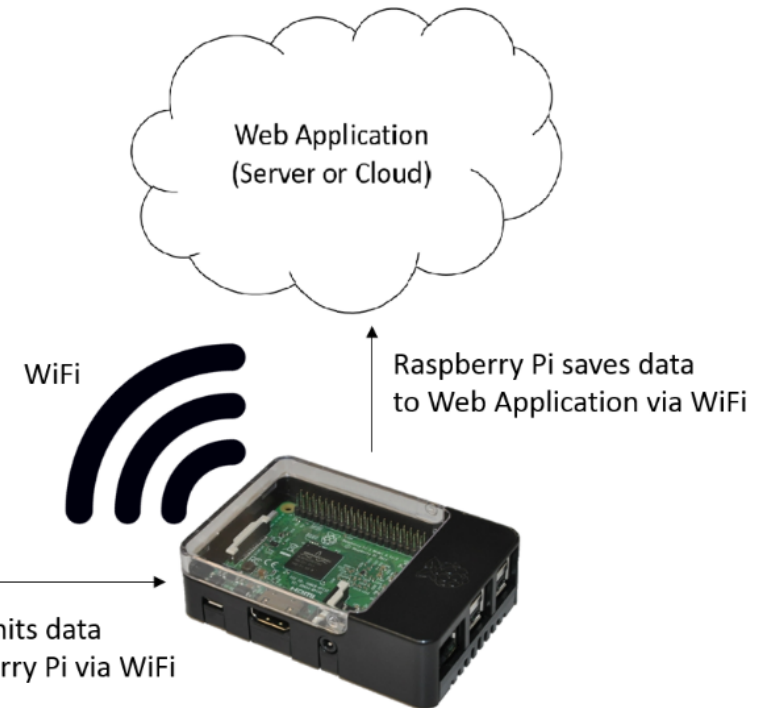
Test Vehicle

Investigated Experiments

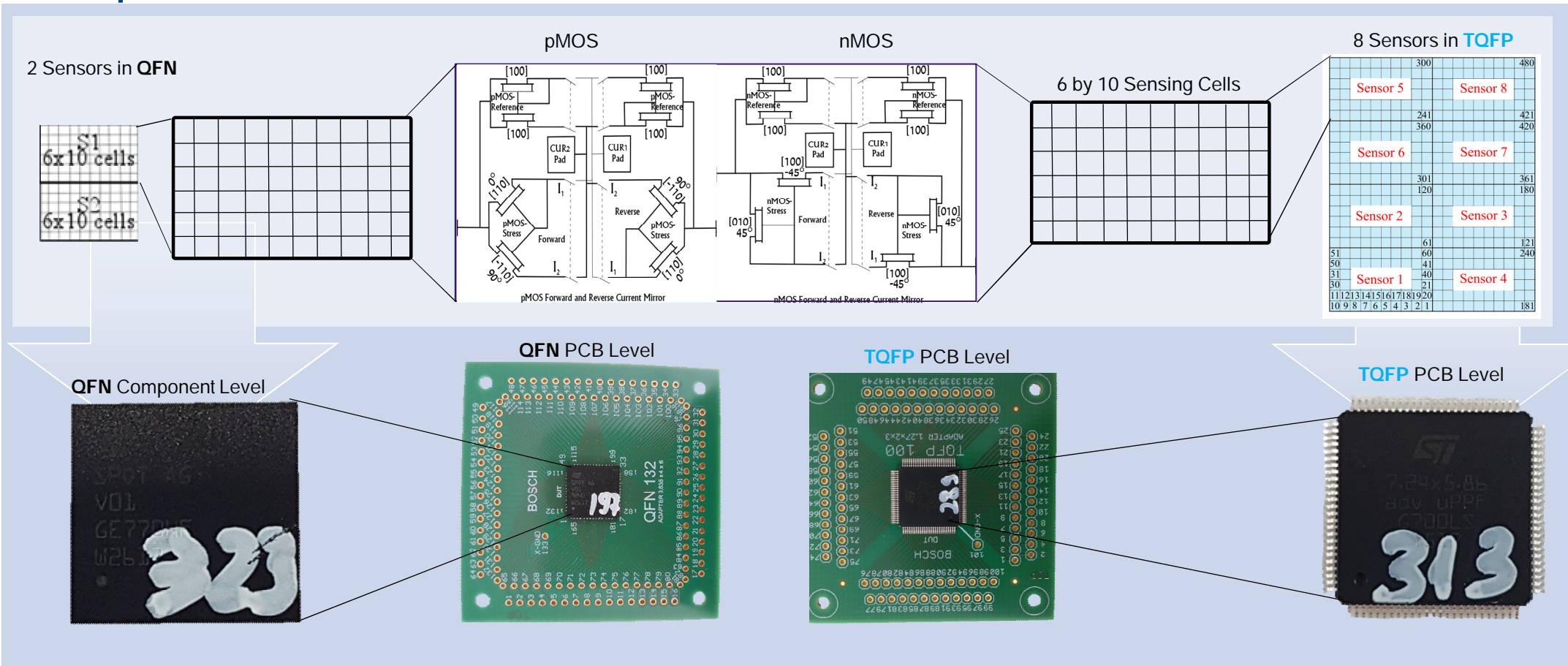
Thermal Shock Chamber



AU transmits data to Raspberry Pi via WiFi



Test Vehicle Components





Thermal Shock Chamber

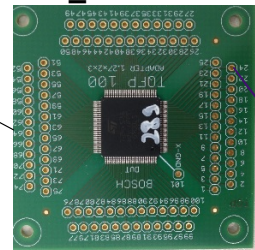
MC2_1



MC2_2

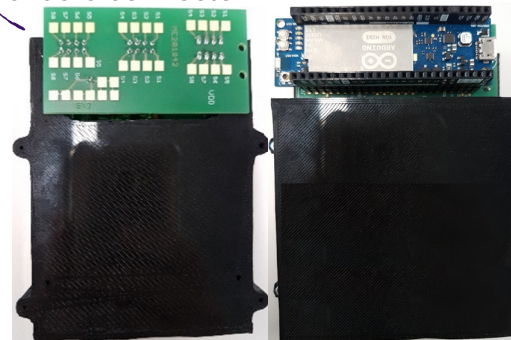


MC1_1



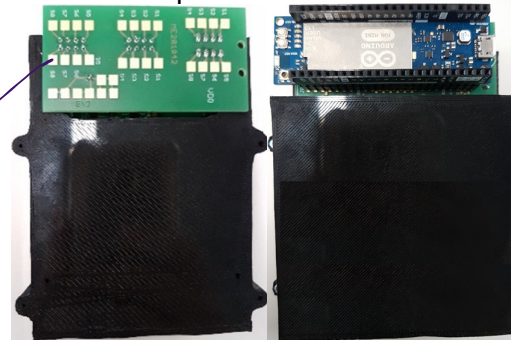
Wires to
Digital I/O
pins

Acquisition Unit 1
Sensors connector
Arduino Board side



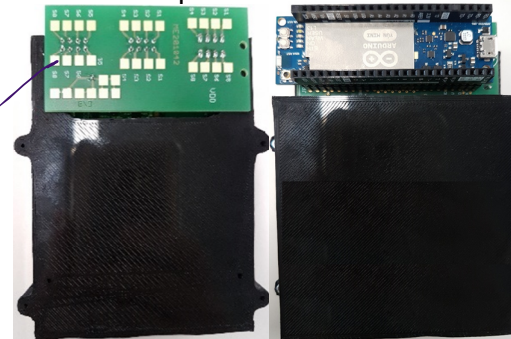
Wires to
Digital I/O
pins

Acquisition Unit 2

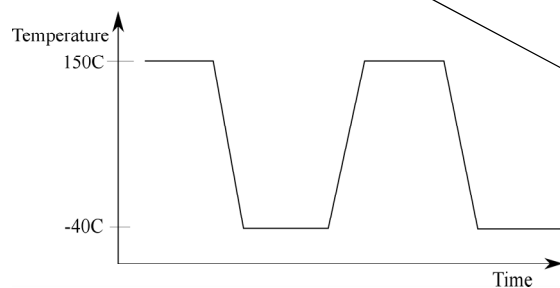


Wires to
Digital I/O
pins

Acquisition Unit 3



WiFi



Results

Feature Extraction

- The resulted stresses are first subtracted from 150C stresses every each cell position and then their absolute values are summed up;

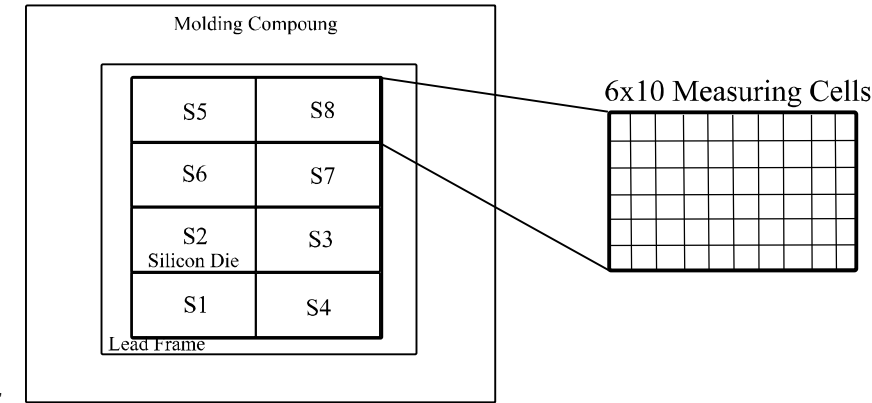
$$f_p^s = \sum_{cell1}^{cell60} |s^{-40C} - s^{150C}| ; p = 1,..,8 \text{ Sensors}; s = \sigma_D, \sigma_{XY}, \tau_{Max}$$

- S can be any of the following stresses:

$$f_p^{\sigma_D} = \sum_{cell1}^{cell60} |\sigma_D^{-40C} - \sigma_D^{150C}| ; p = 1,..,8 \text{ Sensors}; s = \sigma_D, \sigma_{XY}, \tau_{Max}$$

$$f_p^{\sigma_{XY}} = \sum_{cell1}^{cell60} |\sigma_{XY}^{-40C} - \sigma_{XY}^{150C}| ; p = 1,..,8 \text{ Sensors}; s = \sigma_D, \sigma_{XY}, \tau_{Max}$$

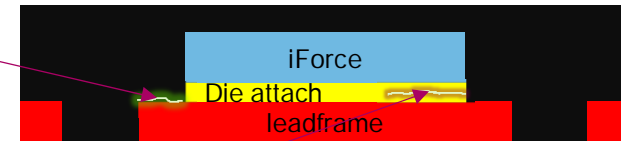
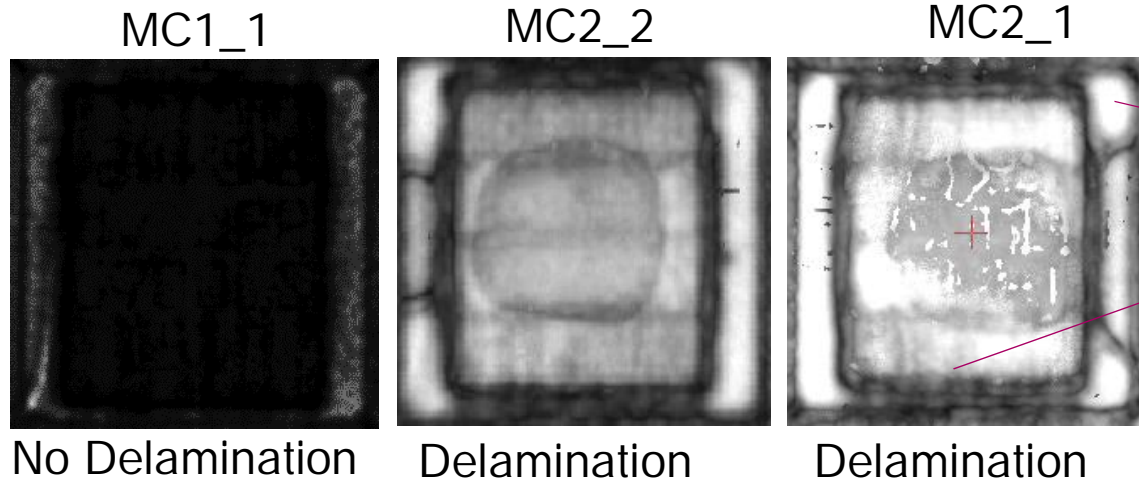
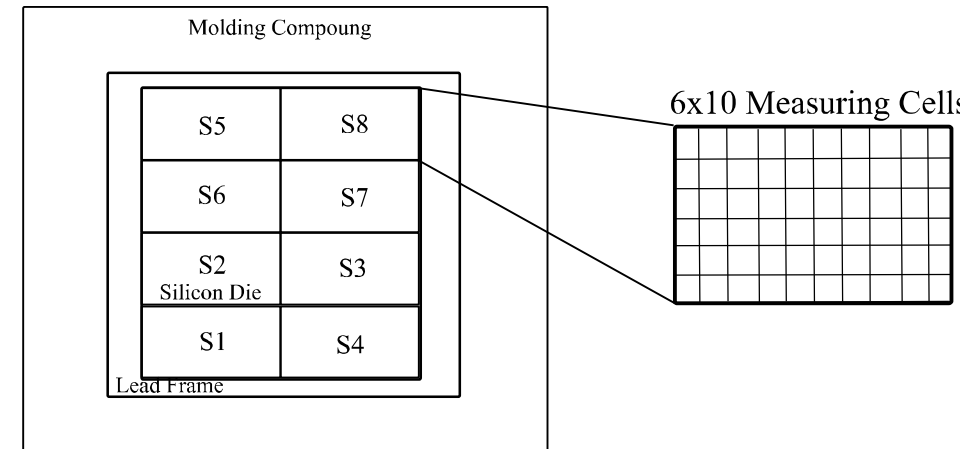
$$f_p^{\tau_{Max}} = \sum_{cell1}^{cell60} |\tau_{Max}^{-40C} - \tau_{Max}^{150C}| ; p = 1,..,8 \text{ Sensors}; s = \sigma_D, \sigma_{XY}, \tau_{Max}$$



Results

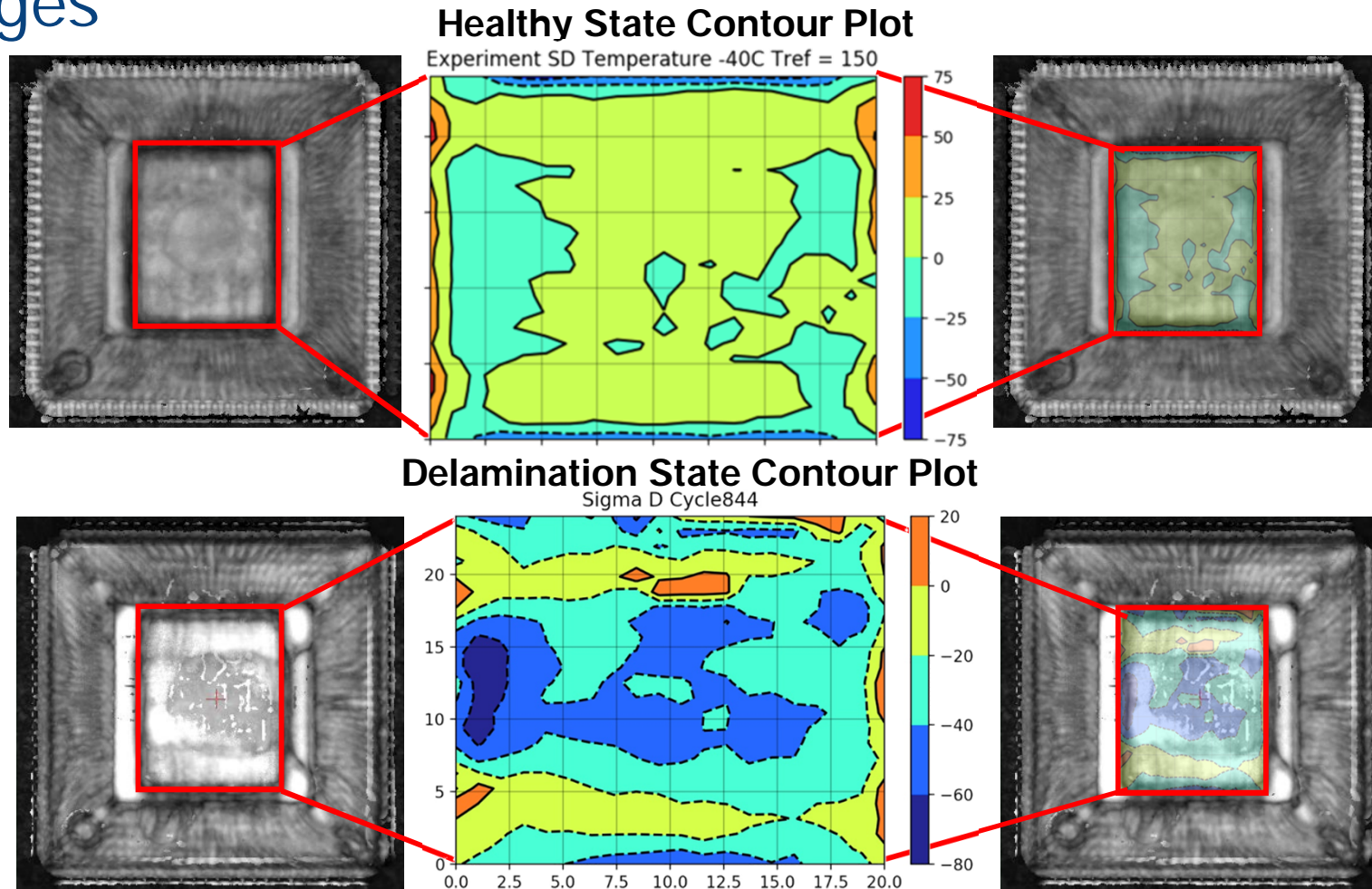
SAM Images

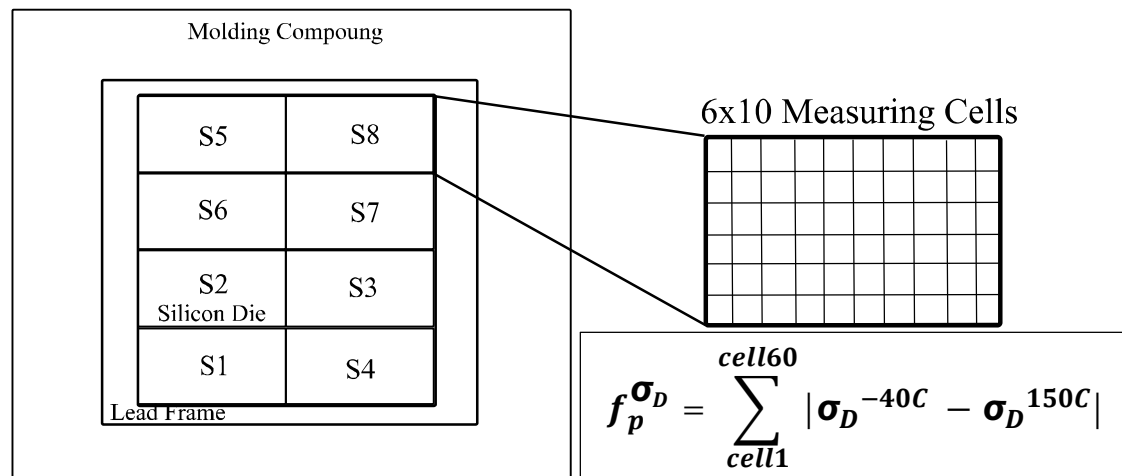
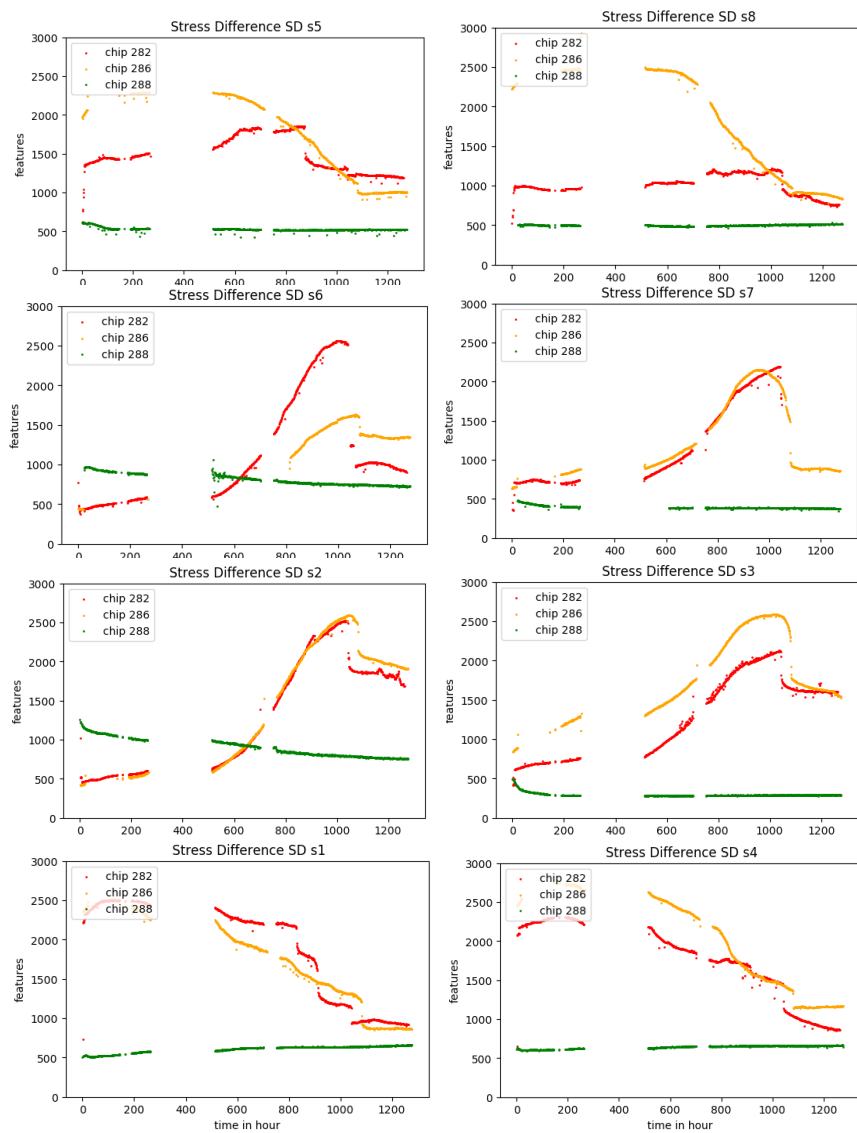
- 2 Delaminated Samples, 1 No delaminated sample



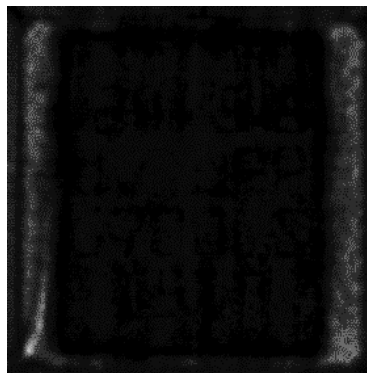
Results

SAM Images

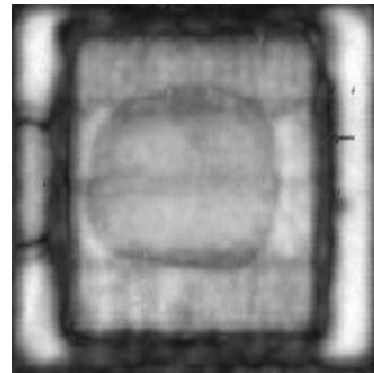




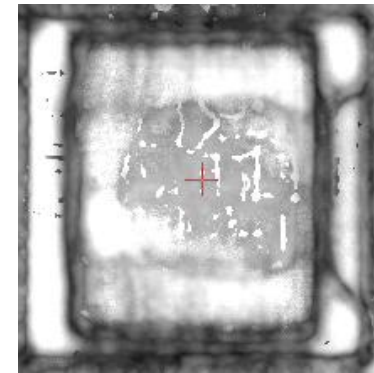
MC1_1



MC2_2

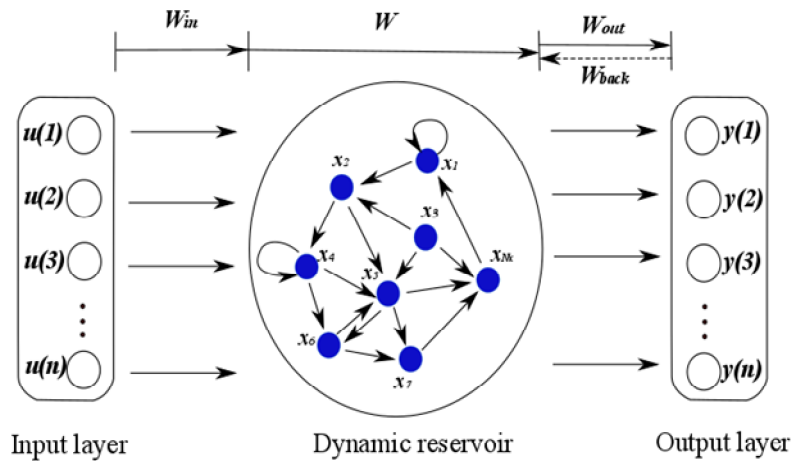


MC2_1



Degradation Prediction

Echo State Network



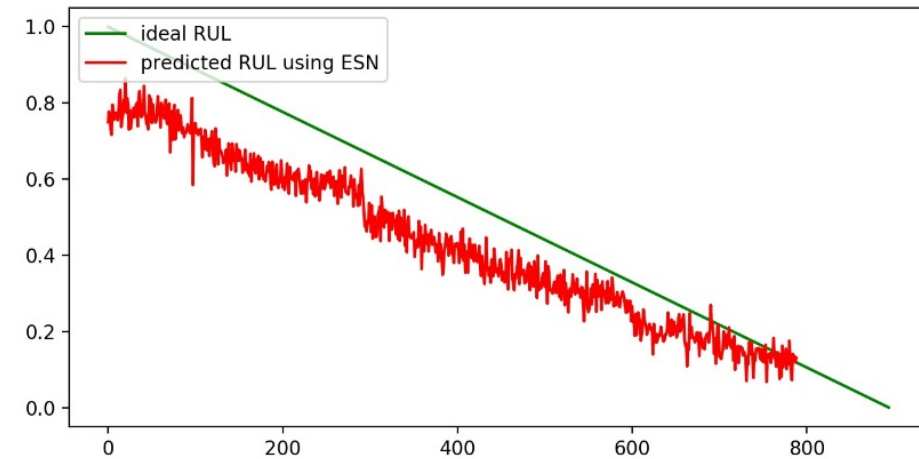
- reservoir size , spectral radius of reservoir
- input shift , input scaling
- output shift , output scaling

Hidden layers->dynamic reservoir

W_{in}, W generated randomly, only W_{out} is trained

$u(1), u(2), \dots, u(n), \dots, u(T)$: stress values during cycling

$y(1), y(2), \dots, y(n), \dots, y(T)$: RUL , 1....0

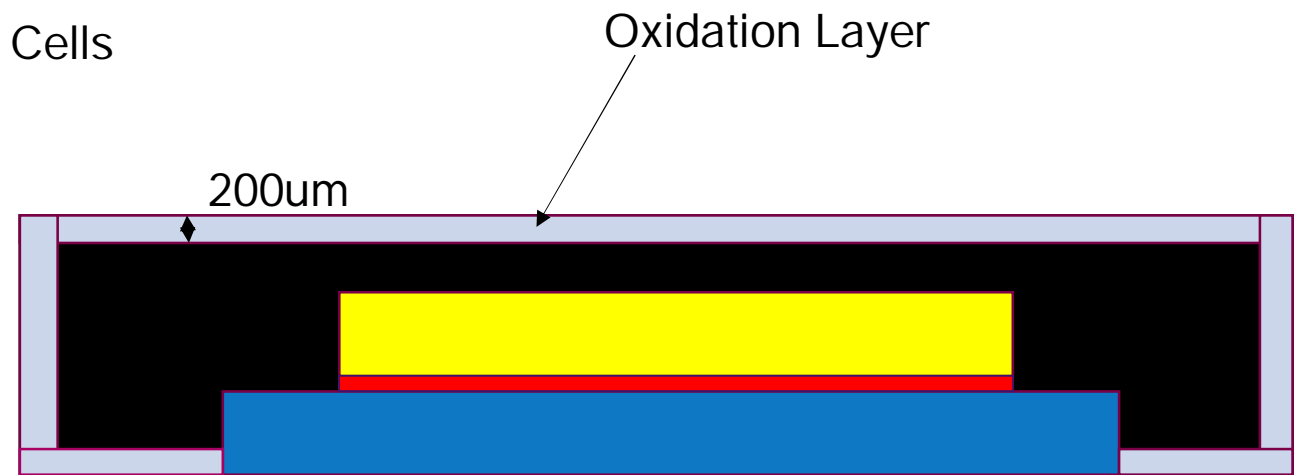
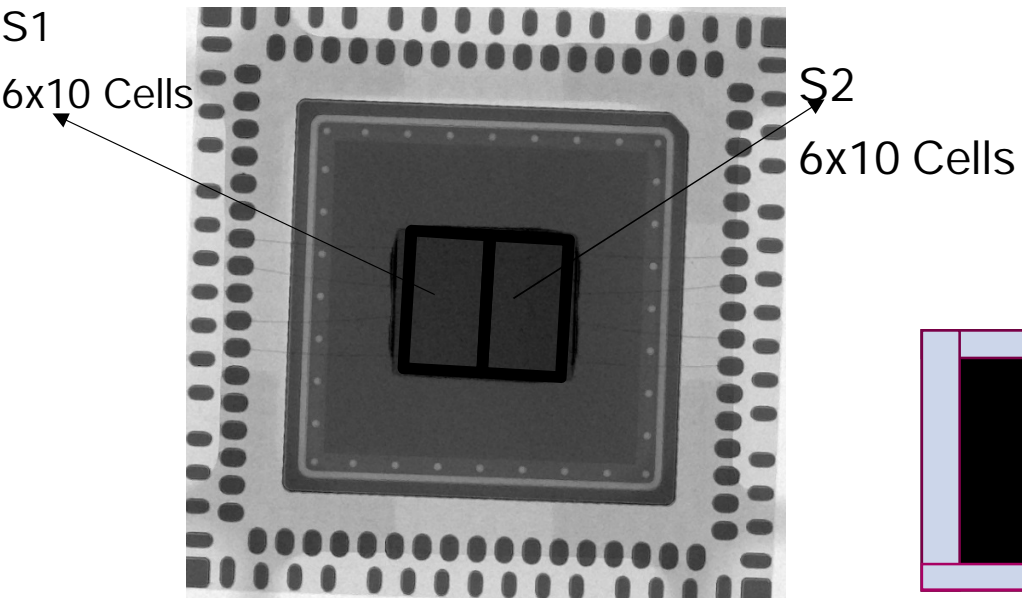


AGING/DRIFTING EFFECTS

*AGING/DRIFTING EFFECTS OF HIGH TEMPERATURE
STORAGE ON STRESS MEASUREMENTS*

Aging Phenomena

Oxidation Layer in Molding Compound

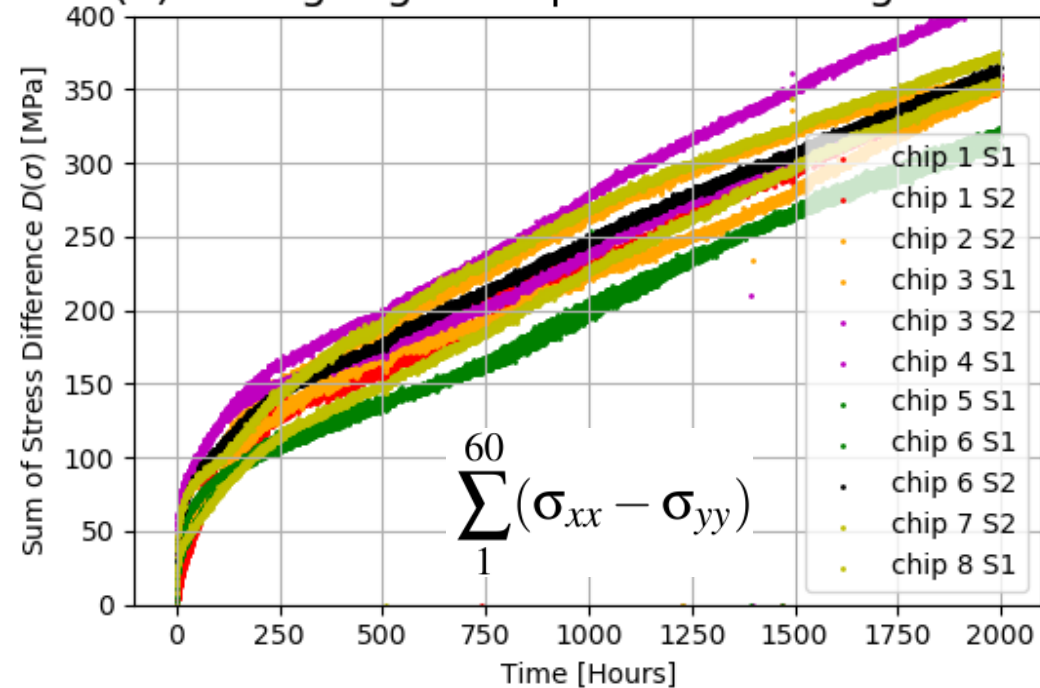


Results

Oxidation Layer in Molding Compound

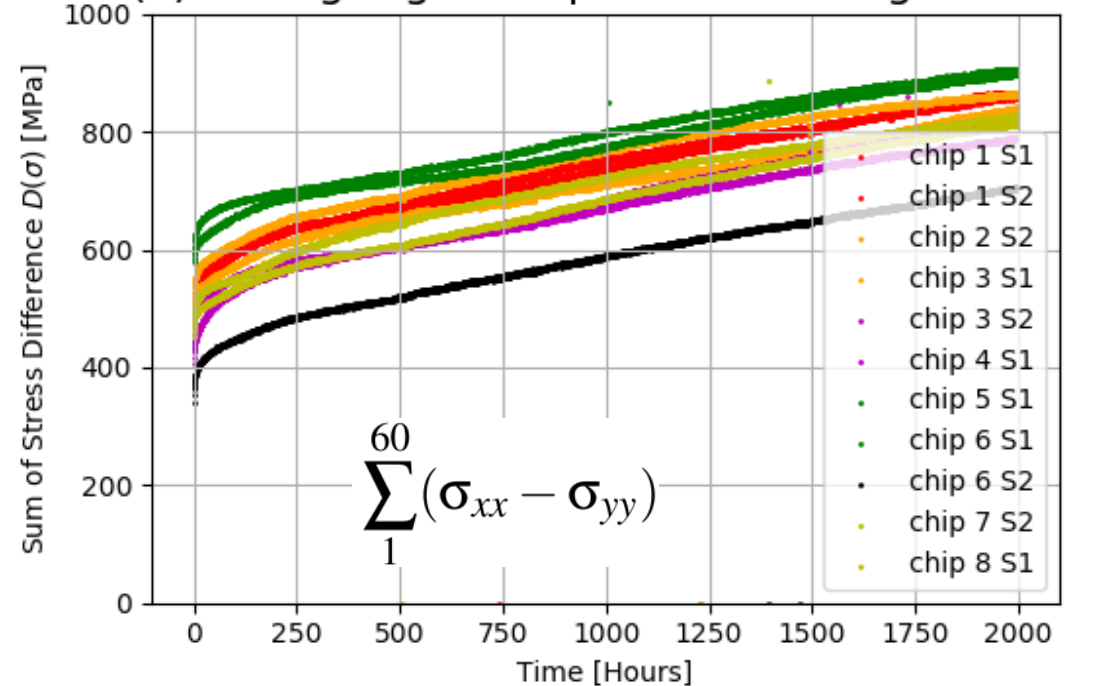
Relative Sum Stresses

$D(\sigma)$ during High Temperature Storage at 150°



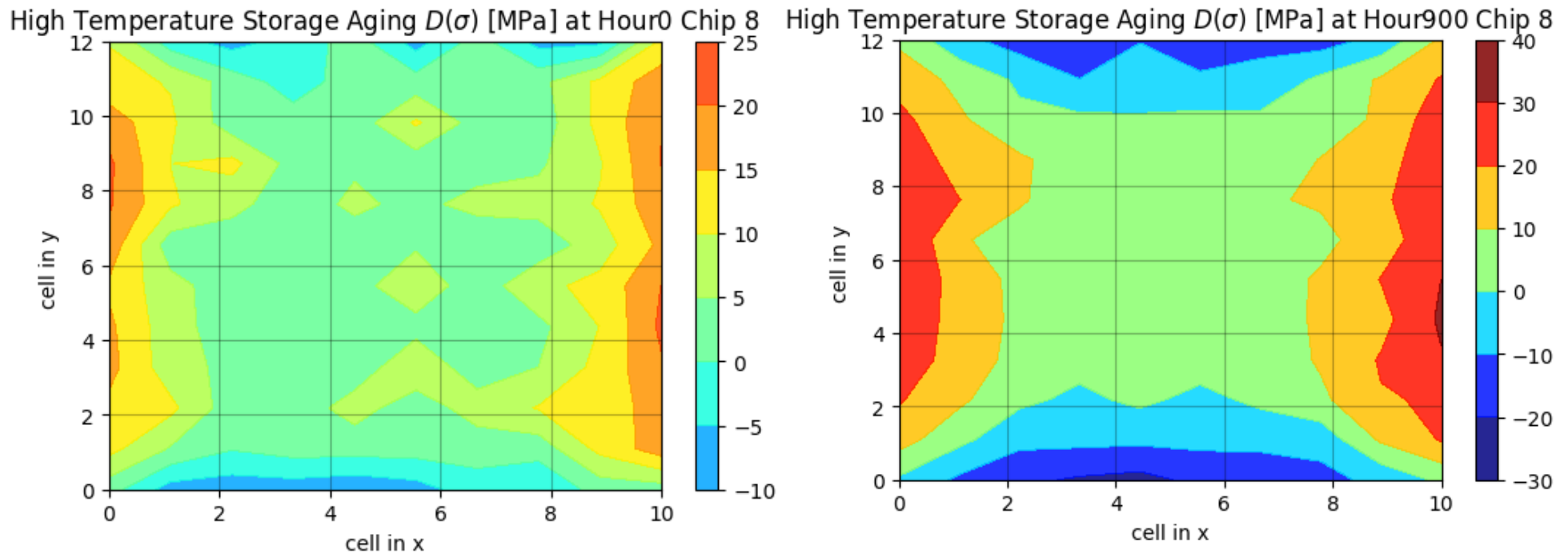
Absolute Sum Stresses

$D(\sigma)$ during High Temperature Storage at 150°



Results

Oxidation Layer in Molding Compound



Stress Difference Contour Plot due to the aging effect